

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/736,386)	
)	Conf. No.: 6227
Filed:	December 15, 2003)	
)	
Title:	METHOD FOR CALCULATING)	
	HIGH-RESOLUTION WAFER)	
	PARAMETER PROFILES)	
)	
Inventor:	Whitefield et al.)	
)	
Art Unit:	2128)	
)	
Examiner:	Kimberly A. Thornwell)	
)	
Atty. Ref:	03-1345)	

RESPONSE TO THE OFFICE ACTION MAILED DECEMBER 26, 2006

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed December 26, 2006, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application.